Low temperature storage test

Experimental objective

To test the influence of low temperature on the sample, thus determine the suitability of sample under low temperature. **High and low temperature chamber** is usually used in this test.

Experimental principle

The component in low temperature, the electronic parameter will change, the material became brittle and produce cold stress. Make the component under low temperature a certain time, and examine whether the electronic parameter change, material became brittle, and how much the stress, thus can determine the component’s ability to resist the low temperature.

Reference standard

JESD22-A119, IEC60068-2-1, GJB1864A-2011

Examples of experimental condition

<table>
<thead>
<tr>
<th>Temperature range</th>
<th>-65±3°C, -55±3°C, -40±3°C, -25±3°C, -10±3°C, -5±3°C, +5±3°C</th>
</tr>
</thead>
<tbody>
<tr>
<td>Test time</td>
<td>96h, 500h, 1000h, 2000h</td>
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</table>